New Jersey Semi-Conductor Products, Inc.

20 STERN AVE.
SPRINGFIELD, NEW JERSEY 07081
U.S.A.

TELEPHONE: (973) 376-2922
(212) 227-6005
FAX: (973) 376-8960

The RF MOSFET Line

RF Power Field-Effect Transistor

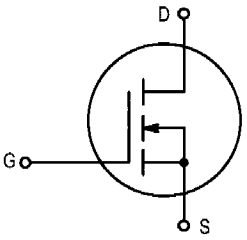
N–Channel Enhancement–Mode

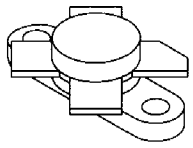
MRF148

Designed for power amplifier applications in industrial, commercial and amateur radio equipment to 175 MHz.

- Superior High Order IMD
- Specified 50 Volts, 30 MHz Characteristics
  Output Power = 30 Watts
  Power Gain = 18 dB (Typ)
  Efficiency = 40% (Typ)
- $IMD_{(d3)}$ (30 W PEP) — −35 dB (Typ)
- $IMD_{(d11)}$ (30 W PEP) — −60 dB (Typ)
- 100% Tested For Load Mismatch At All Phase Angles With 30:1 VSWR

30 W, to 175 MHz
N–CHANNEL MOS
LINEAR RF POWER
FET





CASE 211–07

MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Drain–Source Voltage	V_{DSS}	120	Vdc
Drain–Gate Voltage	V_{DGO}	120	Vdc
Gate–Source Voltage	V_{GS}	±40	Vdc
Drain Current — Continuous	I_D	6.0	Adc
Total Device Dissipation @ T_C = 25°C Derate above 25°C	P_D	115 0.66	Watts W/°C
Storage Temperature Range	T_{stg}	−65 to +150	°C
Operating Junction Temperature	T_J	200	°C

THERMAL CHARACTERISTICS

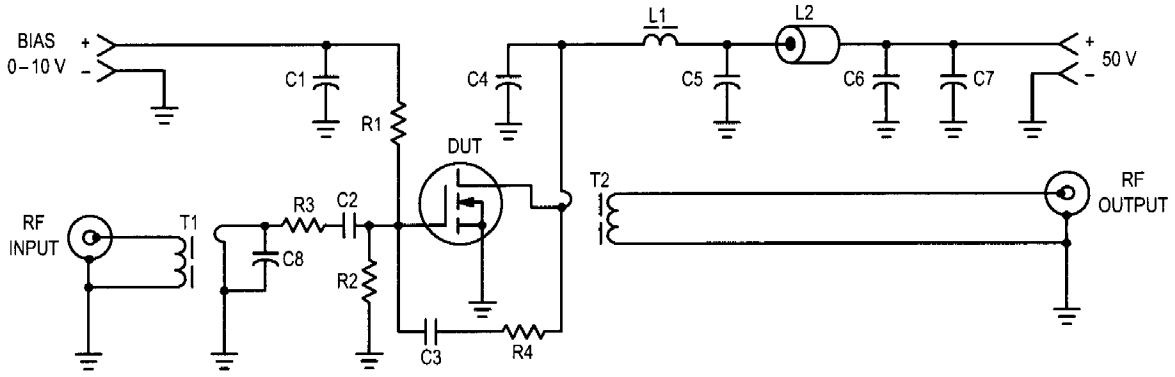
Characteristic	Symbol	Max	Unit
Thermal Resistance, Junction to Case	$R_{\theta JC}$	1.52	°C/W

Handling and Packaging — MOS devices are susceptible to damage from electrostatic charge. Reasonable precautions in handling and packaging MOS devices should be observed.

ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise noted.)

Characteristic	Symbol	Min	Typ	Max	Unit
OFF CHARACTERISTICS					
Drain–Source Breakdown Voltage (V_{GS} = 0, I_D = 10 mA)	$V_{(BR)DSS}$	125	—	—	Vdc
Zero Gate Voltage Drain Current (V_{DS} = 50 V, V_{GS} = 0)	I_{DSS}	—	—	1.0	mAdc
Gate–Body Leakage Current (V_{GS} = 20 V, V_{DS} = 0)	I_{GSS}	—	—	100	nAdc
ON CHARACTERISTICS					
Gate Threshold Voltage (V_{DS} = 10 V, I_D = 10 mA)	$V_{GS(th)}$	1.0	3.0	5.0	Vdc
Drain–Source On–Voltage (V_{GS} = 10 V, I_D = 2.5 A)	$V_{DS(on)}$	1.0	3.0	5.0	Vdc
Forward Transconductance (V_{DS} = 10 V, I_D = 2.5 A)	g_{fs}	0.8	1.2	—	mhos
DYNAMIC CHARACTERISTICS					
Input Capacitance (V_{DS} = 50 V, V_{GS} = 0, f = 1.0 MHz)	C_{iss}	—	50	—	pF
Output Capacitance (V_{DS} = 50 V, V_{GS} = 0, f = 1.0 MHz)	C_{oss}	—	35	—	pF
Reverse Transfer Capacitance (V_{DS} = 50 V, V_{GS} = 0, f = 1.0 MHz)	C_{rss}	—	8.0	—	pF
FUNCTIONAL TESTS (SSB)					
Common Source Amplifier Power Gain (30 MHz) (V_{DD} = 50 V, P_{out} = 30 W (PEP), I_{DQ} = 100 mA) (175 MHz)	G_{ps}	— —	18 15	— —	dB
Drain Efficiency (30 W PEP) (V_{DD} = 50 V, f = 30 MHz, I_{DQ} = 100 mA) (30 W CW)	η	— —	40 50	— —	%
Intermodulation Distortion (V_{DD} = 50 V, P_{out} = 30 W (PEP), f = 30; 30.001 MHz, I_{DQ} = 100 mA)	$IMD_{(d3)}$ $IMD_{(d11)}$	— —	−35 −60	— —	dB
Load Mismatch (V_{DD} = 50 V, P_{out} = 30 W (PEP), f = 30; 30.001 MHz, I_{DQ} = 100 mA, VSWR 30:1 at all Phase Angles)	ψ	No Degradation in Output Power			
CLASS A PERFORMANCE					
Intermodulation Distortion (1) and Power Gain (V_{DD} = 50 V, P_{out} = 10 W (PEP), f1 = 30 MHz, f2 = 30.001 MHz, I_{DQ} = 1.0 A)	G_{PS} $IMD_{(d3)}$ $IMD_{(d9-13)}$	— — —	20 −50 −70	— — —	dB

NOTE:
1. To MIL–STD–1311 Version A, Test Method 2204B, Two Tone, Reference Each Tone.



C1, C2, C3, C4, C5, C6 — 0.1 μF Ceramic Chip or Equivalent
C7 — 10 μF, 100 V Electrolytic
C8 — 100 pF Dipped Mica
L1 — VK200 20/4B Ferrite Choke or Equivalent (3.0 μH)
L2 — Ferrite Bead(s), 2.0 μH
R1, R2 — 200 Ω, 1/2 W Carbon
R3 — 4.7 Ω, 1/2 W Carbon
R4 — 470 Ω, 1.0 W Carbon
T1 — 4:1 Impedance Transformer
T2 — 1:2 Impedance Transformer

Figure 1. 2.0 to 50 MHz Broadband Test Circuit